

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	746	(test\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:09
S2	882	(test\$4 or detect\$4 or measur\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/12 09:48
S3	6017	324/765, "158""."1".ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:03
S4	190	((test\$4 or detect\$4 or measur\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))) and (324/765, "158""."1".ccls.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:55
S5	49	(((test\$4 or detect\$4 or measur\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))) and (324/765, "158""."1".ccls.)) and row	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:21
S6	8	test\$4 near5 (plurality adj (integrated adj circuit or IC!) near5 (row or column))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:26
S7	2	test\$4 near5 (plurality adj (integrated adj circuit or IC!) with (row or column))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:26
S8	10132	324/754-765.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:27
S9	251	((test\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))) and 324/754-765.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:27
S10	519691	control\$4 near5 switch	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 15:56

S11	125	((test\$4 or detect\$4 or measur\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))) and (control\$4 near5 switch)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 16:07
S12	608	324/760.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 16:09
S13	2	(control\$4 near5 switch) and (((test\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))) and 324/760. ccls.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 16:09
S14	36	((test\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))) and 324/760. ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 16:15
S15	55931	(test\$4 or detect\$4) near5 ((integrated adj circuit or IC!))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 16:40
S16	564521	control\$4 near5 (switch or relay)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 14:28
S17	5431	((test\$4 or detect\$4) near5 ((integrated adj circuit or IC!))) and (control\$4 near5 (switch or relay))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 14:28
S18	8671	324/765,760,158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 14:29
S19	306	(((test\$4 or detect\$4) near5 ((integrated adj circuit or IC!))) and (control\$4 near5 (switch or relay))) and 324/765,760,158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 14:29
S20	4	("5794175" "5969537" "6297659" "6329831").PN.	USPAT	OR	ON	2004/11/08 15:09
S21	1745	(test\$4 or detect\$4) near5 ((integrated adj circuit or IC!)) with transistor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 16:41

S22	0	((test\$4 or detect\$4) near5 ((integrated adj circuit or IC!)) with transistor) and incrementor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 16:42
S23	147	((test\$4 or detect\$4) near5 ((integrated adj circuit or IC!)) with transistor) and counter	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 16:42
S24	44	(((test\$4 or detect\$4) near5 ((integrated adj circuit or IC!)) with transistor) and counter) and decoder	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 17:28
S25	126283	logic adj circuit	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 17:28
S26	5125	((test\$4 or detect\$4) near5 ((integrated adj circuit or IC!))) and (logic adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 17:28
S27	893	(logic adj circuit) with (counter and decoder)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 17:29
S28	29	((logic adj circuit) with (counter and decoder)) and ((test\$4 or detect\$4) near5 ((integrated adj circuit or IC!)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/08 17:29
S29	1	10/478121	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 18:25
S30	884	(test\$4 or detect\$4 or measur\$4) near5 plurality adj3 ((integrated adj circuit or IC!) or (test adj structure))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/12 09:49
S31	40741	decoder and increment\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/12 09:49

S32	28	S30 and S31	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/12 10:24
S33	48	S31 and 324/765,158.1,763,760. ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/12 10:51
S34	219	S30 and 324/765,158.1,763,760. ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/12 10:52
S35	55	S34 and row	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/12 10:52
S36	150799	(test\$4 or detect\$4 or measur\$4) near5 (test adj structure or integrated adj circuit or IC! or chip or wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:14
S37	6771	324/760-765,158.1.cccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:10
S38	4056	S36 and S37	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:11
S39	314	trigger\$4 adj signal with (row or column)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:11
S40	3	S38 and S39	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:11
S41	2159	(test\$4 or detect\$4 or measur\$4) near5 (test adj structure or integrated adj circuit or IC! or chip or wafer) with (row or column)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:44

S42	195	S37 and S41	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:15
S43	0	(test\$4 or detect\$4 or measur\$4) near5 (test adj structure or integrated adj circuit or IC! or chip or wafer) with ("row by row")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:45
S44	245	(test\$4 or detect\$4 or measur\$4) near5 (test adj structure or integrated adj circuit or IC! or chip or wafer) with (row near5 row)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:52
S45	25	S44 and S37	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:45
S46	9910	(test\$4 or detect\$4 or measur\$4) near5 (test adj structure or integrated adj circuit or IC! or chip or wafer) with plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:52
S47	1317	S37 and S46	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:52
S48	5504	(test\$4 or detect\$4 or measur\$4) near5 (test adj structure or integrated adj circuit or IC! or chip or wafer) near3 plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:53
S49	881	S37 and S48	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:53
S50	700	S49 and (control\$4 or computer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 14:54
S51	7	S50 and (trigger\$4 adj signal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:01

S52	28551	(Parallel adj (logic device or circuit) tester).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:03
S53	0	(Parallel adj (logic device or circuit) adj tester).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:03
S54	0	(Parallel adj (logic device/circuit) adj tester).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:03
S55	0	(Parallel adj (logic device) adj tester).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:05
S56	18513	testing adj2 plurality adj2 memory chips adj3 wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:17
S57	2	bidirectional adj comparator adj2 detectors	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:16
S58	1	S57 and S56	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:07
S59	31480	"714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:16
S60	45	testing adj2 plurality adj2 chips adj3 wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:17
S61	5	S59 and S60	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/28 15:17

S62	0	(test\$4 or measur\$4) near5 (plurality adj3 (integrated adj circuit or IC or transistor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 11:03
S63	110	(test\$4 or measur\$4) near5 (row adj3 (integrated adj circuit or IC or transistor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 11:10
S64	8860	324/765,158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 11:04
S65	21	S64 and S63	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 11:10
S66	0	(test\$4 or measur\$4) near5 (each adj3 row)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 11:11
S67	0	(test\$4 or measur\$4) near5 (each near5 row)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 11:11
S68	0	"10696,320"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 11:18
S69	0	("10,696,320").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/02 11:18
S70	0	(10/696,320).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/02 11:19
S71	2	("4972144").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/02 11:19